

D. Thin Film Process Technology 분과

2017년 2월 14일 (화), 16:00-17:30
Room A (에메랄드, 2층)

[TA3-D] Oxide Thin Film Transistors

좌장: 최리노(인하대학교), 김성근(한국과학기술연구원)

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| TA3-D-1 16:00-16:15 | Characterization of P-Type SnO Thin Films Grown by Atomic Layer Deposition and its Application to TFTs Younjin Jang, Junshik Kim, Eunsuk Hwang, Seungjun Lee, and Cheol Seong Hwang <i>Department of Materials Science and Engineering and Inter-university Semiconductor Research Center, Seoul National University</i> |
| TA3-D-2 16:15-16:30 | Effect of Microwave Irradiation on the Charge Trapping and Detrapping Characteristics in Amorphous in-Ga-ZnO Thin-Film-Transistors. Hyun-Woo Lee and Won-Ju Cho <i>Department of Electrical Materials Engineering, Kwnagwoon University</i> |
| TA3-D-3 16:30-16:45 | Analysis of Defects and Charge Trapping Behavior of Double Active Layer In-Zn-O and Al-Sn-Zn-O Thin Film Transistor Youngin Goh ¹ , Teaho Kim ¹ , Jong-Heon Yang ² , Ji Hun Choi ² , Chi-Sun Hwang ² , Sung Haeng Cho ² , and Sanghun Jeon ¹ <i>¹Department of Applied Physics, Korea University, ²Electronics Telecommunications Research Institute (ETRI)</i> |
| TA3-D-4 16:45-17:00 | Investigation on Low Temperature Sol-Gel Derived ZnO Thin Film Transistors Seong-Won Chae ¹ , Ho-Jin Yun ² , Seung-Dong Yang ² , Jae-Gab Lim ² , Jun-Kyo Jeong ² , Jung-Hyun Park ² , Yu-Jeong Kim ² , Hyo-Jin Kim ³ and Ga-Won Lee ^{1,2} <i>¹Graduate school of Advanced Circuit Substrate Engineering, Chungnam National University, ²Department of Electronics Engineering, Chungnam National University, ³Department of Materials Science and Engineering, Chungnam National University</i> |
| TA3-D-5 17:00-17:15 | Channel Shape Dependency on Device Reliability of Amorphous Indium-Gallium-Zinc-Oxide Thin Film Transistors Seung Jae Yu, Jae Hyun Ryu, Geun Woo Baek, Jong Hun Hong, and Sung Hun Jin <i>Department of Electronic Engineering, Incheon National University</i> |